

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number PESD15VW1BCSF Part Description													
											NXP ICN8	Protection IND)I		
									Assembly reliability labs		BD package				
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects									
	TEST														
	Pre- and Post-Stress														
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below									
		MIL-STD-750-1													
	HTRB	M1038 Method A													
		Tj = Tjmax, Vr = 100% of max. datasheet													
# 5	Bias	reverse voltage	1000 hours	68	4040	0									
	TC	JESD22-A104													
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	109	6440	0									
		JECD33 4110													
# 0	UHAST Unbiased HAST	JESD22-A118													
# 8 or	Undiased HAST	Tamb = 130 °C, RH = 85 %	96 hours	n.a.	n.a.	n.a.									
		JESD22-A102													
	AC	Tamb = 121 °C, RH = 100 %													
# 8a	Autoclave	Pressure = 205 kPa (29.7 psia)													
		JECD22 4410													
	HAST	JESD22-A110 Tamb = 130 °C, RH = 85%, VR = 80 % of													
	Highly Accelerated Stress Test	rated reverse voltage ^[1]				_									
# 9	rest		1000 hours	108	6400	0									
		MIL-STD-750 Method 1037													
	IOL	ton = toff, devices powered to insure ΔTj =													
# 10	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.									
	DCII.	JECD22 A111													
	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C													
# 20		200 °C ± 5 °C	10 s	n.a.	n.a.	n.a.									
	SD Coldorobility	1 CTD 003				_									
# 21	Solderability	J-STD-002		18	180	0									

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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